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(Rev. 8-83)U.S. Department of Commerce
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Atty Docket 0756-2414

Serial No.

INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: December 28, 2001

Group Art Unit:

Unassigned



U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
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08	10-132749	05/22/1998	JP	—	—	X	

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JP	Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", pp. 571-578, May 1, 1988, Japanese Journal of Applied Physics, Vol. 27, No. 5

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		Filing Date: December 28, 2001	Group Art Unit: 2673	
OTHER DOCUMENT (Including Author, Title, Date, Pertinent Pages, Etc.)				
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<i>DJ</i>	Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", pp. 751-758, May 1, 1988, Japanese Journal of Applied Physics, Vol. 27, No. 5			
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